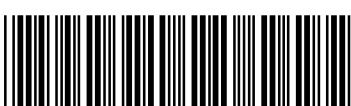


Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10760300	CHEN ET AL.
	Examiner	Art Unit
	SHANELL HEIBER	2617

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
See updated EAST search report	10/17/08	SLH

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	See EAST search report	10/17/08	SLH

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